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Integrated circuits - EMC evaluation of transceivers -
Part 2: LIN transceivers

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

See Eesti standard EVS-EN 62228-2:2017 sisaldb Euroopa standardi EN 62228-2:2017 ingliskeelset teksti.	This Estonian standard EVS-EN 62228-2:2017 consists of the English text of the European standard EN 62228-2:2017.
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ICS 31.200

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EUROPEAN STANDARD
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English Version

Integrated circuits - EMC evaluation of transceivers -
Part 2: LIN transceivers
(IEC 62228-2:2016)

Circuits intégrés - Évaluation de la CEM des émetteurs-récepteurs - Partie 2: Émetteurs-récepteurs LIN
(IEC 62228-2:2016)

Integrierte Schaltungen - Bewertung der elektromagnetischen Verträglichkeit von Sende-Empfangsgeräten - Teil 2: LIN-Sende-Empfangsgeräte
(IEC 62228-2:2016)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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European foreword

The text of document 47A/994/FDIS, future edition 1 of IEC 62228-2, prepared by SC 47A "Integrated circuits" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62228-2:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2017-09-23
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2019-12-23

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 1: General conditions and definitions	EN 61967-1	-
IEC 61967-4	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 4: Measurement of conducted emissions - 1 ohm/150 ohm direct coupling method	EN 61967-4	-
IEC 62132-1	-	Integrated circuits - Measurement of electromagnetic immunity - Part 1: General conditions and definitions	EN 62132-1	-
IEC 62132-4	-	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz - Part 4: Direct RF power injection method	EN 62132-4	-
IEC 62215-3	-	Integrated circuits - Measurement of impulse immunity - Part 3: Non-synchronous transient injection method	EN 62215-3	-
ISO 7637-2	-	Road vehicles - Electrical disturbances from conduction and coupling - Part-2: Electrical transient conduction along supply lines only	-	-
ISO 10605	-	Road vehicles - Test methods for electrical - disturbances from electrostatic discharge	-	-
ISO 17987-6	-	Road vehicles - Local Interconnect Network (LIN) - Part 6: Protocol conformance test specification	-	-

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